

## SM8007NSU-VB Datasheet

# N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY							
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$ Max.	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)				
	0.0050 at V <sub>GS</sub> = 10 V	75 <sup>a</sup>					
80	0.0070 at V <sub>GS</sub> = 6.0 V	65 <sup>a</sup>	17.1 nC				
	0.0087 at V <sub>GS</sub> = 5.0 V	54					

# **FEATURES**

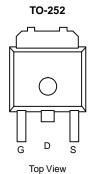


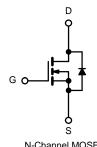
- Trench Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested



#### **APPLICATIONS**

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting





N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	80	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20	V	
	T <sub>C</sub> = 25 °C		75 <sup>a</sup>		
Continuous Dunis Comment /T 150 °C)	T <sub>C</sub> = 70 °C		62.7		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	28.6 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		24.9 <sup>b, c</sup>		
Pulsed Drain Current (t = 100 μs)		I <sub>DM</sub>	150	A	
Continuous Courses Dunis Dinds Coursest	T <sub>C</sub> = 25 °C	,	75a		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	4.5 <sup>b, c</sup>		
Single Pulse Avalanche Current	. 0.1 11	I <sub>AS</sub>	30		
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	45	mJ	
	T <sub>C</sub> = 25 °C		62.5		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	5	40	W	
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	5 <sup>b</sup> , c		
	T <sub>A</sub> = 70 °C		3.2 <sup>b, c</sup>		
Operating Junction and Storage Temperature R	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	00		
Soldering Recommendations (Peak Temperature		260	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 10 s	R <sub>thJA</sub>	20	25	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	1.5	2.0	C/VV	

#### **Notes**

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- d. The TO-220 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70  $^{\circ}\text{C/W}.$



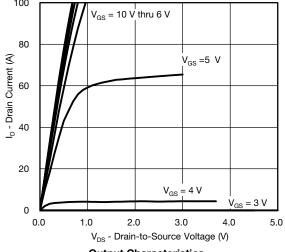
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			37			
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 6.1		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th</sub> )	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.5		4.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
	, ,	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		0.0050			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 6 \text{ V}, I_D = 15 \text{ A}$		0.0070		Ω	
	, ,	$V_{GS} = 5.0 \text{ V}, I_D = 10 \text{ A}$		0.0087			
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		60		S	
Dynamic <sup>b</sup>							
out Capacitance C <sub>iss</sub>			1855				
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		950		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			76			
		$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5	54		
Total Gate Charge	$Q_g$	$V_{DS} = 40 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 10 \text{ A}$		22	33	1	
				17.1	26	nC	
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3			
Gate-Drain Charge	$Q_{gd}$			7.3		1	
Output Charge	Q <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86		
Gate Resistance	$R_g$	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			12	24		
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$		8	16		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10^{\circ} \text{A}, V_{GEN} = 10^{\circ} \text{V}, R_g = 1^{\circ} \Omega$		32	64		
Fall Time	t <sub>f</sub>			7	14	1	
Turn-On Delay Time	t <sub>d(on)</sub>			14	28	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_{L} = 4 \Omega$		11	22	-	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_g = 1 \Omega$		30	60		
Fall Time	t <sub>f</sub>			8	16		
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C			75	۸	
Pulse Diode Forward Current (t = 100 μs)	I <sub>SM</sub>				150	A	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 5 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			38	75	ns	
Body Diode Reverse Recovery Charge	Recovery Charge O			36	70	nC	
Reverse Recovery Fall Time	ta			19		ns	
Reverse Recovery Rise Time	t <sub>b</sub>			19			

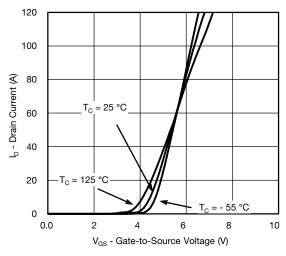
#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

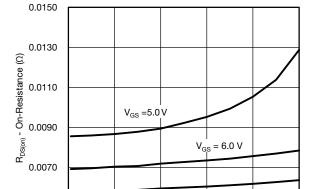
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



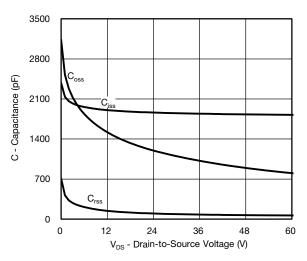








**Transfer Characteristics** 



# I<sub>D</sub> - Drain Current (A) On-Resistance vs. Drain Current

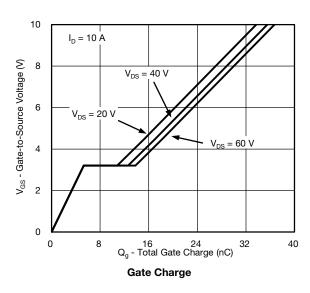
60

40

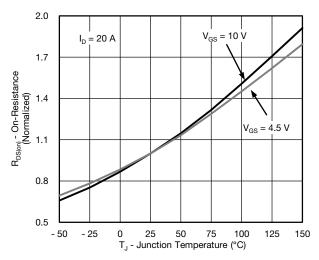
 $V_{GS} = 10 \text{ V}$ 

100

80



Capacitance



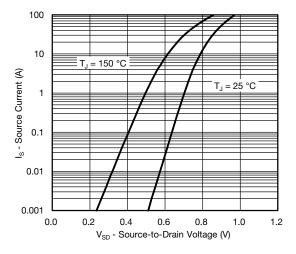
On-Resistance vs. Junction Temperature

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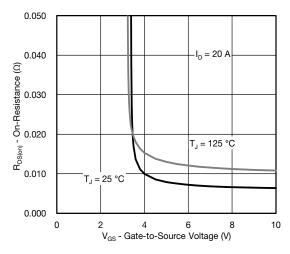
0.0050

0

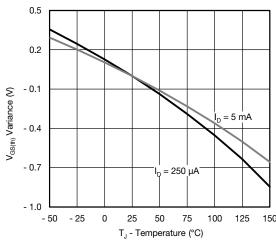




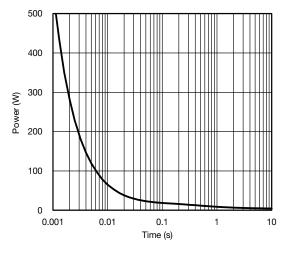
Source-Drain Diode Forward Voltage



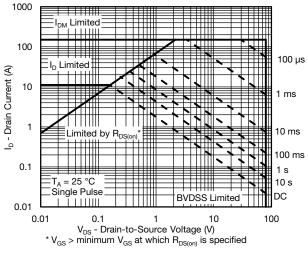
On-Resistance vs. Gate-to-Source Voltage



**Threshold Voltage** 

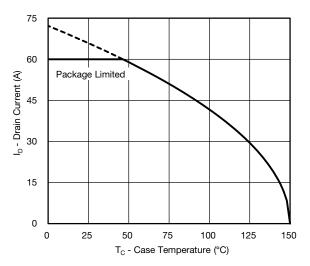


Single Pulse Power, Junction-to-Ambient

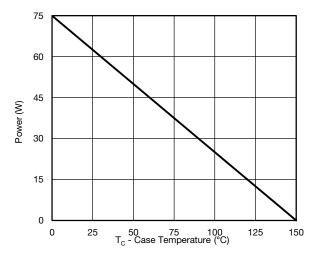


Safe Operating Area, Junction-to-Ambient

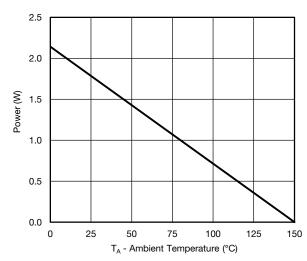




#### **Current Derating\***



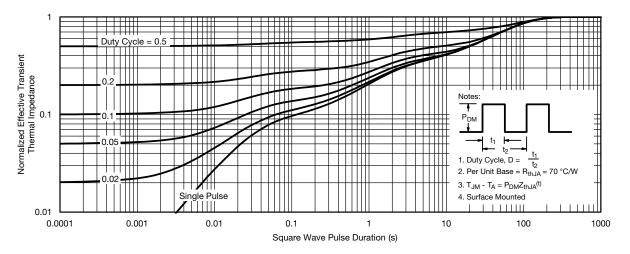




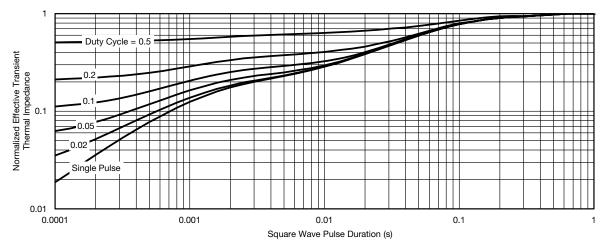
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





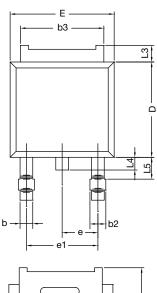
Normalized Thermal Transient Impedance, Junction-to-Ambient

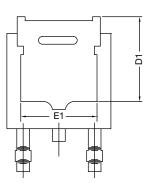


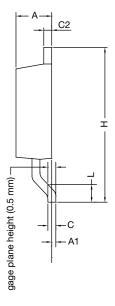
Normalized Thermal Transient Impedance, Junction-to-Case



## **TO-252AA CASE OUTLINE**







	MILLIMETERS		INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	5.21	-	0.205	-		
Е	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28	B BSC 0.090 BS		BSC		
e1	4.56 BSC		0.180 BSC			
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.14	1.52	0.045	0.060		
ECN: X12-0247-Rev. M. 24-Dec-12						

ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347

#### Note

• Dimension L3 is for reference only.

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7



### **RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)**



Recommended Minimum Pads Dimensions in Inches/(mm)



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